SN54276, SN74276 QUADRUPLE J.K FLIP-FLOPS

SDLS091

OCTOBER 1976 - REVISED MARCH 1988

- Four J-K Flip-Flops in a Single Package . . .
 Can Reduce FF Package Count by 50%
- Separate Negative-Edge-Triggered Clocks with Hysteresis . . . Typically 200 mV
- Typical Clock Input Frequency . . . 50 MHz
- Fully Buffered Outputs

description

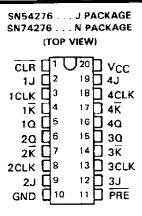
These quadruple TTL J-K flip-flops incorporate a number of third-generation IC features that can simplify system design and reduce flip-flop package count by up to 50%. They feature hysteresis at each clock input, fully buffered outputs, and direct clear capability, and are presettable through a buffer that also features an input hysteresis loop. The negative-edge-triggering clocks are directly compatible with earlier Series 54/74 single and dual pulse-triggered flip-flops. These circuits can be used to emulate D- or T-type flip-flops by hard-wiring the inputs, or to implement asychronous sequential functions.

The SN54276 is characterized for operation over the full military temperature range of -55° C to 125° C; the SN74726 is characterized for operation from 0° C to 70° C.

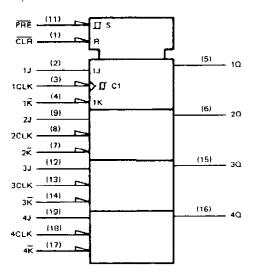
FUNCTION TABLE (EACH FLIP-FLOP)

COMMON INPUTS		INPUTS			QUTPUT		
PRE	CLR	CLK	CLK J K		a		
L	Н	х	Х	Х	Н		
н	L	×	X	×	L		
L	L	×	х	х	H [†]		
н	Н		L	Н	α_0		
н	Н		н	н	н		
н	н	ļ i	L	L	L		
H	Н	1	Н	L	TOGGLE		
Н	Н	н	×	×	00		

[†] This configuration is nonstable; that is, it may not oersist when preset and clear return to their inactive (high) level.



logic symbol[‡]

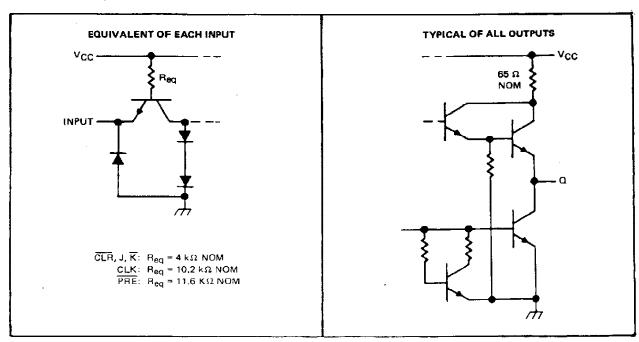


*This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

PRODUCTION DATA documents centain information current as of publication date. Products conform to specifications per the terms of Texes Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



schematics of inputs and outputs



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	7 V
Input voltage		5.5 V
Operating free-air temperature range:	SN54276	55°C to 125°C
	\$N74276	0° C to 70° C
Storage temperature range		- 65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



recommended operating conditions

		SN54276		SN74276			UNIT	
	_	MIN	NOM	MAX	MIN	NOM	MAX	JUNIT
Supply voltage, V _{CC}		4.5	5	5.5	4,75	5	5.25	V
High-level output current, IOH				-800			-800	μА
Low-level output curi	rent, IOL	1		16			16	mA
Clock frequency		0		35	0		35	MHz
	Clock high	13.5			13,5			
Pulse width, t _W	Clock low	15			15			ns
	Preset or clear low	12			12			
Setup time, t _{su}	J, K inputs	3t			34			ns
	Clear and preset inactive state	10↓			10↓			
Input hold time, th	•	10↓			104			ns
Operating free-air temperature, TA		-55		125	0		70	°C

¹ The arrow indicates that the falling edge of the clock pulse is used for reference.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONST		MIN	TYP‡	MAX	UNIT
VIH	High-level input voltage			2			V
VIL	Low-level input voltage				-	8.0	V
ViK	Input clamp voltage	V _{CC} = MIN,	1 ₁ = -12 mA			-1.5	٧
V _{ОН}	High-level output voltage	V _{CC} = MIN, V _{IL} = 0.8 V,	V _{IH} = 2 V, I _{OH} = –800 µA	2.4	3.4		V
v _{OL}	Low-level output voltage	V _{CC} = MIN, V _{1L} = 0.8 V,	V _{IH} = 2 V, I _{OL} = 16 mA		0.2	0.4	V
t ₁	Input current at maximum input voltage	V _{CC} = MAX,	V = 5.5 V		-	1	пΑ
і н	High-level input current	VCC = MAX,	V ₁ = 2.4 V			40	μА
*1L	Low-level input current	V _{CC} ≃ MAX,	V ₁ = 0.4 V	1		-1.6	mA
los	Short-circuit autput current§	V _{CC} = MAX		-30		85	mΑ
lcc	Supply current	V _{CC} = MAX			60	81	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, V_{CC} = 5 V, T_A = 25 °C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f	Maximum clock frequency		35	50		MHz
^I max [†] PLH	Propagation delay time, low-to-high-level output from preset	C _L = 15 pF.		15	25	ns
^T PHL	Propagation delay time, high-to-low-level output from clear	R _L = 400 Ω.		18	30	ns
^t PLH	Propagation delay time, low-to-high level output from clock	See Note 2		17	30	ns
tPHL	Propagation delay time, high-to-low level output from clock			20	30	กร

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



[‡]All typical values are at V_{CC} = 5 V, T_A = 25°C.

 $[\]S Not \, more \, than \, one \, output should be shorted at a time.$

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